

Focused Test, Inc. (FTI) and Seica Inc. invite you to visit the Seica booth #2061 at this year's Semicon West–Moscone Center, San Francisco, July 12-14, 2022.

FTI will demonstrate its FTI 1000 test system, configured to perform Dynamic Rdson test of GaN HEMT and <2ns Pulse Width test of an EPC LiDAR GaN IC for Time of Flight, 'Driverless Anything' applications.

FTI 1000's flexible architecture provides a high degree of scalability for a wide range of power discrete and IC test applications, and offers significant reduction in cost of test.